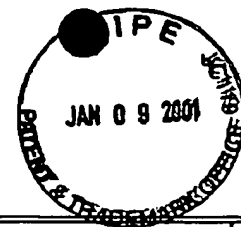


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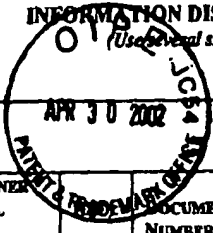
Sheet 1 of 1

FORM PTO-1449 (Modified) (Rev. 7-80)		U.S. Dept. of Commerce Patent and Trademark Office		Atty Docket No. TWI-10820		Appln. No. 09/629,407	
INFORMATION DISCLOSURE CITATION  (Use several sheets if necessary)				Applicant(s) Allan Rosencwaig et al.			
				Filing Date August 1, 2000		Group 2876	
U.S. PATENT DOCUMENTS							
*Examiner Initials		Document Number	Date	Name	Class	Subclass	Filing Date
HKS	AA	5,371,582	12/06/1994	Toba et al.	356	73	07/30/1993
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*Examiner Initials		Document Number	Date	Country	Class	Subclass	Translation YES NO
HKS	AE	0 352 740	07/25/1989	BPC	H01L	21/306	
HKS	AF	EP 0 768 512	10/15/1996	EPC	G01B	11/06	
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OTHER DOCUMENTS							
	AH						
	AI						
Examiner  Hoon Song				Date Considered  2/26/04			
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	TWI-10820	09/629,407
	<b>Applicant(s)</b>	
	Allan Rosencwaig et al.	
	<b>Filing Date</b>	<b>Group Art Unit</b>
	August 1, 2000	2876



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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
HE2	CA	WO 01/71325	09/27/2001	PCT	G01N	23/00		

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HKS	CB	E. Loken et al., "Growth monitoring of W/Si X-ray multilayers by X-ray reflectivity and kinetic ellipsometry," SPIE, Vol. 2253, November 1994, pp. 327-332.						

<b>Examiner</b> <i>Heon Song</i>	<b>Date Considered</b> <i>2/26/04</i>
<b>Examiner:</b> Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include Copy of this form with next communication to applicant.	

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